

A method to plan & generate IO ring based on csv specifications

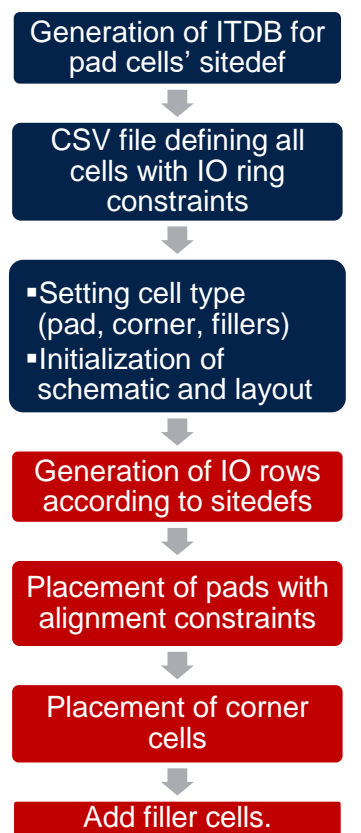
Manvi Dhawan, Rajeev Singh, Atul Bhargava from STMicroelectronics
Akshita Bansal, Hitesh Marwah, Vishesh Kumar from Cadence

1 Motivation

- For Testchip design IO ring is created for testing IPs and needs to be aligned with the board.
- Specifications for testchip placement are layout driven and available with layout designer.
- Generation of IO ring involves placement of pads, fillers, and corners aligned perfectly.
- Wirebond cells are placed on an outer ring for connection with board.
- To ensure the quality of design it takes many iterations to clean DRC and make the placement even.

2 Flow overview

- Incremental tech file to match placement in rows with cell dimensions.
 - Single user input capturing all placement specification.
 - Full connectivity established between layout and schematic generated.
 - All the spaces filled automatically with filler cells to ensure continuity in placement.
 - Customized automated flow over Virtuoso IO planner.
- Customized automated flow
■ Tool features from Virtuoso



3 Incremental technology database

- Incremental database is generated over technology database with additional information about sitedefs for row placement.
- Row height should match the height should match the height of pad cells to be placed in rows.
- To be created for each type of cell placement.

```
scalarSiteDefs(
;siteDefName type width height symInX symInY symInR0)
;-----
;corner pad 40.015 40.015 nil nil nil)
(it_pad_1 pad 0.1 40.015 nil nil nil)
(it_pad_2 pad 0.1 60 nil nil nil)
);scalarSiteDefs
);siteDefs
```

Fig1: sample incremental tech file for site definitions

4 Assisted placement setup

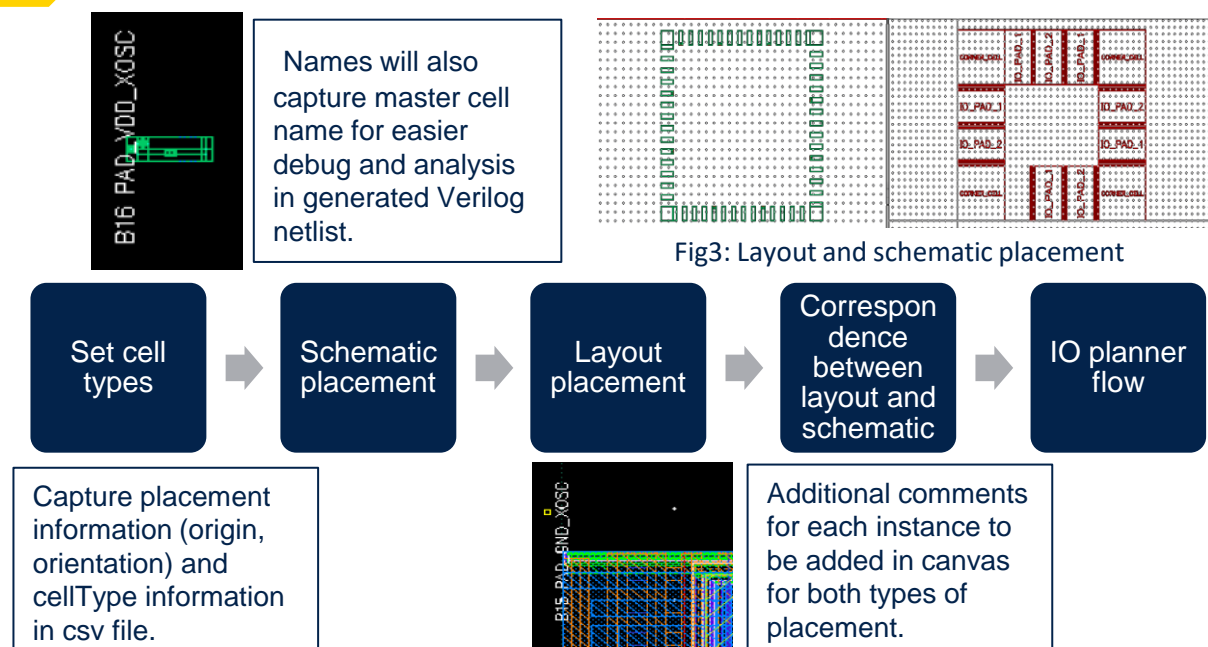
- Generation of schematic and layout placements.**
 - Layout designer can capture placement specification and cell type in csv format.

#id_name	cell_name	view_name	relative_spacing	origin	direction	alignment	cellType	comment	Instance_prefix
C28S01_IO_EXT_CSF_BASIC_EG	LBCORNERCELL_EXT_CSF_FC_LIN	layout	nil	0 0	nil	R0	corner		
C28S01_IO_EXT_CSF_BASIC_EG	VDD_EXT_CSF_FC_LIN	layout	10nil	up	R270	pad	B16 PAD_VDD_XOSC	PAD_VDD_XOSC	
C28S01_IO_WBPAD_6U1X2U2X2T8XLB	PAD_WB45SR_6U1X2U2X2T8XLB_V5_10ML	layout	10nil	up	R270	pad			
C28S01_IO_EXT_CSF_BASIC_EG	GND_EXT_CSF_FC_LIN	layout	150nil	up	R270	pad	B15 PAD_GND_XOSC	PAD_GND_XOSC	
C28S01_IO_WBPAD_6U1X2U2X2T8XLB	PAD_WB45SR_6U1X2U2X2T8XLB_V5_10ML	layout	10nil	up	R270	pad			
C28S01_IO_EXT_ALIF_ESDHUB_EG	FILLCELL_ESDHUB_EXT_CSF_FC_LIN	layout	10nil	up	R270	pad			
C28S01_IO_EXT_CSF_GPIO1V8_FSNFS_LR_B8DPROGSCRUDQP_EXT_CSF_1V8_FS_FC_LIN		layout	100nil	up	R270	pad	B14 Global_Enable	Global_Enable	
C28S01_IO_WBPAD_6U1X2U2X2T8XLB	PAD_WB45SR_6U1X2U2X2T8XLB_V5_10ML	layout	10nil	up	R270	pad			

Fig2: Sample input CSV file capturing user specifications

- The cellType for cells are set through skill script for IO planner, based on user specification in csv file.
 - Even if cells are in read only access, cell type is set for placement in current session.
- Additional information for comments and instance name can be captured through CSV.

5 Generation of schematic and layout placement



6 Generation of IO ring

- Automatic IO planner will place pad cells based on their cell types definition as pad cells.
- Cell type is also defined to identify corner cells and filler cells.
- To ensure that order of pad cells is as per user requirement, select the pads and set *alignment* constraint to preserve order.

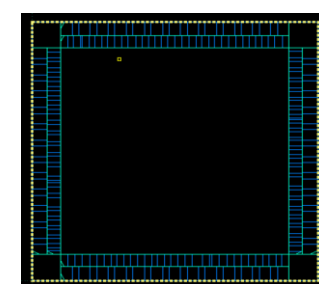
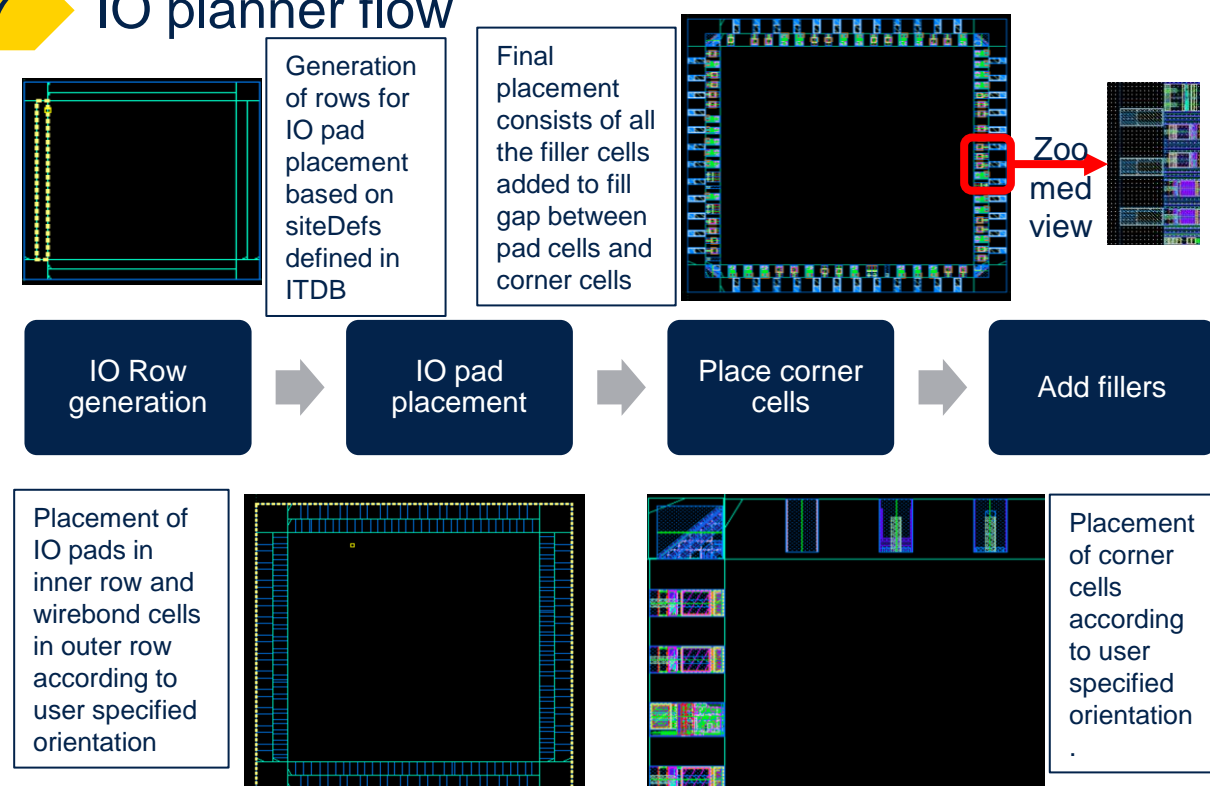


Fig4: IO pads placement on respective sides

7 IO planner flow



8 Summary

- We need to make test chips for all analog IPs.
 - There is **no schematic available**.
 - It takes **3-4 weeks** for manually making the test chip.
 - About **10-15 test chips** are delivered every year.
- The flow proposed provides a semiautomated flow that
 - Saves **40% effort**.
 - Eliminates manual error prone** placements that are CSV based in the flow.
 - Quality of the layout improves** as wire bond cells are distributed evenly.
- The flow is **technology independent** and **can be reused** for generation of multiple test chips.